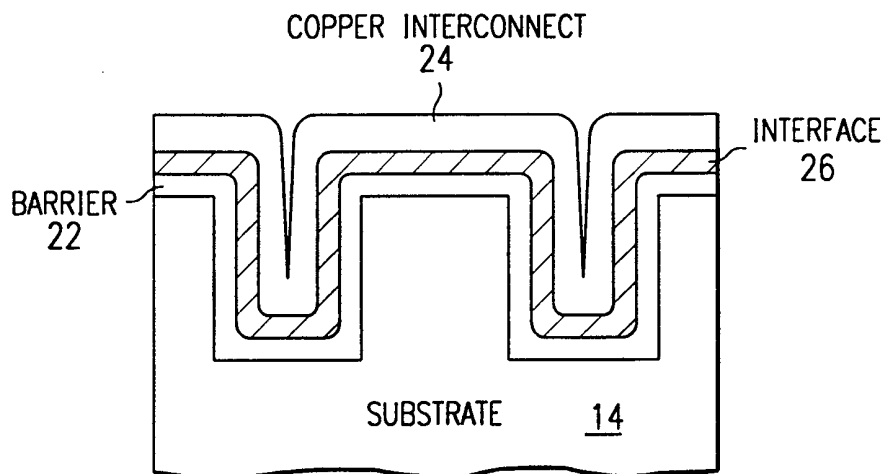




INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

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(21) International Application Number: PCT/US99/15583 (22) International Filing Date: 9 July 1999 (09.07.99) (30) Priority Data: 09/113,852 10 July 1998 (10.07.98) US (71) Applicant: CVC, INC. [US/US]; 525 Lee Road, Rochester, NY 14603 (US). (72) Inventors: PARANJPE, Ajit, P.; 355 North Wolfe Road #336, Sunnyvale, CA 94086 (US). MOSLEHI, Mehrdad, M.; 956 Stanley Avenue, Los Altos, CA 94024 (US). VELO, Lino, A.; P.O. Box 2690, San Ramon, CA 94583 (US). OMSTEAD, Thomas, R.; 4201 Bowstring Cove, Austin, TX 78735 (US). CAMPBELL, David, R., Sr.; 33 Littlewood Lane, West, Rochester, NY 14625 (US). LIU, Zeming; 13408 Caballero Cove, Austin, TX 78727 (US). SHANG, Guihua; 825 East Evelyn Avenue #620, Sunnyvale, CA 94086 (US). (74) Agent: HOLLAND, Robert, W.; Baker & Botts, L.L.P., 2001 Ross Avenue, Dallas, TX 75201-2980 (US).		(81) Designated States: AE, AL, AM, AT, AT (Utility model), AU, AZ, BA, BB, BG, BR, BY, CA, CH, CN, CU, CZ, CZ (Utility model), DE, DE (Utility model), DK, DK (Utility model), EE, EE (Utility model), ES, FI, FI (Utility model), GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MD, MG, MK, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, SK (Utility model), SL, TJ, TM, TR, TT, UA, UG, UZ, VN, YU, ZA, ZW, ARIPO patent (GH, GM, KE, LS, MW, SD, SL, SZ, UG, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GW, ML, MR, NE, SN, TD, TG). Published <i>With international search report.</i> (88) Date of publication of the international search report: 29 June 2000 (29.06.00)

(54) Title: METHOD FOR FORMING A COPPER FILM ON A SUBSTRATE



(57) Abstract

Adhesion of a copper film, such as a copper interconnect (24), to a substrate underlayer, such as a substrate diffusion barrier, is enhanced with adhesion promotion techniques. The adhesion promotion techniques can repair the interface (26) of the copper film and the substrate to enhance adhesion of the copper film for high-yield formation of inlaid copper metal lines and plugs. For instance, thermal annealing of a seed layer, including a copper seed layer, an alloy seed layer or a reactant seed layer, can repair contamination at the interface of the seed layer and the substrate. Alternatively, the adhesion promotion techniques can avoid contamination of the interface by depositing an inert seed layer, such as a noble (e.g., platinum) or passivated metal seed layer, or by depositing the seed layer under predetermined conditions that minimize contamination of the interface, and then depositing a bulk copper layer under predetermined conditions that maximize throughput. Alternatively, the adhesion promotion techniques can avoid the formation of an interface by graduated deposition of a first material and copper.

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INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 99/15583

A. CLASSIFICATION OF SUBJECT MATTER

IPC 7 H01L21/285 C23C16/02

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L C23C

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
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Y	page 49, left-hand column, paragraph 2 -page 51, right-hand column, paragraph 2; figures 1,3	4-6,70
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Further documents are listed in the continuation of box C.



Patent family members are listed in annex.

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- * & * document member of the same patent family

Date of the actual completion of the international search

7 April 2000

Date of mailing of the international search report

11.04.00

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INTERNATIONAL SEARCH REPORT

International Application No
PCT/US 99/15583

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

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Y	EP 0 698 918 A (TEXAS INSTRUMENTS INC ;CALIFORNIA INST OF TECHN (US)) 28 February 1996 (1996-02-28) page 6, line 1 - line 3 ---	70
Y	US 5 112 448 A (CHAKRAVORTY KISHORE K) 12 May 1992 (1992-05-12) column 3, line 37 -column 5, line 43; figures 13A,14 ---	6
A	PATENT ABSTRACTS OF JAPAN vol. 1998, no. 09, 31 July 1998 (1998-07-31) & JP 10 092977 A (INTERNATL BUSINESS MACH CORP <IBM>), 10 April 1998 (1998-04-10) abstract -& US 5 866 237 A (ANGELOPOULOS ANASTASIOS PETER ET AL) 2 February 1999 (1999-02-02) column 2, line 24 - line 32 ---	1,11,13
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P,X	EP 0 881 673 A (IBM) 2 December 1998 (1998-12-02) column 9, line 27 -column 10, line 28 column 11, line 19 - line 32; figures 3,4 -----	1,11,13

INTERNATIONAL SEARCH REPORT

International application No.
PCT/US 99/15583

Box I Observations where certain claims were found unsearchable (Continuation of item 1 of first sheet)

This International Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:

1. ☐ Claims Nos.:
because they relate to subject matter not required to be searched by this Authority, namely:
2. ☐ Claims Nos.:
because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:
3. ☐ Claims Nos.:
because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).

Box II Observations where unity of invention is lacking (Continuation of item 2 of first sheet)

This International Searching Authority found multiple inventions in this international application, as follows:

see additional sheet

1. ☐ As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.
2. ☐ As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.
3. ☒ As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:
1-6, 11-16, 69-71
4. ☐ No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:

Remark on Protest

- ☐ The additional search fees were accompanied by the applicant's protest.
- ☒ No protest accompanied the payment of additional search fees.

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. Claims: 1-6,69-71

Before depositing a bulk copper film, depositing a seed layer consisting of a noble metal.

2. Claims: 7-10

Before depositing a bulk copper film, depositing a passivated metal (TaN,TiN,TaOxNy,TiOxNy) as a seed layer.

3. Claims: 11-16

Before depositing a bulk copper film, depositing a catalytic material (Cr,Sn,Zn,Ti,W) as a seed layer.

4. Claims: 17-21

Before depositing a bulk copper film, depositing a seed layer of a reactant material (Si,Ge).

5. Claims: 22-24

Before depositing a bulk copper film, depositing a copper seed layer.

6. Claims: 25-30

Before depositing a bulk copper film, depositing a seed layer by CVD from a precursor with firmly bonded hfac ligands.

7. Claims: 31-38

Before depositing a bulk copper film, depositing a seed layer by CVD from a precursor that has no hfac-ligands.

8. Claims: 39-52

Before depositing a bulk copper film, depositing a seed layer on a barrier layer and performing thermal annealing.

9. Claims: 53-68

Before depositing a bulk copper film, depositing a first

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

material at a first deposition rate and grading the first material with copper, slowly reducing the first deposition rate to zero.

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/US 99/15583

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